

<b>Notice of References Cited</b>	Application/Control No. 10/563,162		Applicant(s)/Patent Under Reexamination SCANLAN, PHILIP	
	Examiner JIALONG HE		Art Unit 2626	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,993,471 B1	01-2006	Flanagan et al.	704/2
*	B	US-5,987,402 A	11-1999	Murata et al.	704/2
*	C	US-6,275,789 B1	08-2001	Moser et al.	704/7
*	D	US-2001/0044809 A1	11-2001	Parasnis et al.	707/513
*	E	US-6,338,033 B1	01-2002	Bourbonnais et al.	704/3
*	F	US-6,345,243 B1	02-2002	Clark, Jonathan P.	704/2
*	G	US-2002/0123878 A1	09-2002	Menke, Laura Lee	704/2
*	H	US-2002/0173946 A1	11-2002	Christy, Samuel T.	704/2
*	I	US-2002/0193983 A1	12-2002	Tokieda et al.	704/2
*	J	US-6,623,529 B1	09-2003	Lakritz, David	715/205
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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